CADD/CCC Conference Call Agenda

July 27, 2016

1. Attendance/ Introductions
   - Julie Lamberson, MO DOT
   - Jason Krogman, MN DOT
   - Maribel Wong, AASHTO
   - Paul E. Sullivan, AZ DOT
   - Melinda Winkelman, IL DOT
   - Chengsheng Ouyang, IA DOT
   - Merrill E Zwanka, SC DOT
   - Temple Short, SC DOT
   - Bin Shi, UT DOT
   - Anita Vuckovska, WR Meadows
   - James M Parry, WI DOT
   - Wilma A Morrison, AET
   - Julia Johnson, AET
   - Cyler Hayes, AET
   - Mark E Piechuta, BASF
   - Nate Artman, SIKA

2. Changes to the work plans
   - CADD:
     - Update all references to MSDS to SDS
     - Section 4.1.1 does not exist, please remove
     - Remove all year references from both work plans
     - Update specification references section to include ASTM E 70
     - IR scans – wait for input
       - Clarify wet or dry material
       - Change 32 to 16 scans
         - Selenium crystal, germanium crystal, or diamond crystal
     - Fee section
• Add uniformity testing only information
  o CCC
    ▪ Section 7.2 change reference to “Section 4”
    ▪ IR scan section revision
3. Manufacturer’s concerns
  • Logistics of option to submit only to uniformity testing
    i. Contact liaison prior to submission
4. Other items?
  • Next Quarterly Call Scheduled for: **Wednesday October 26th, 1pm Eastern Time**